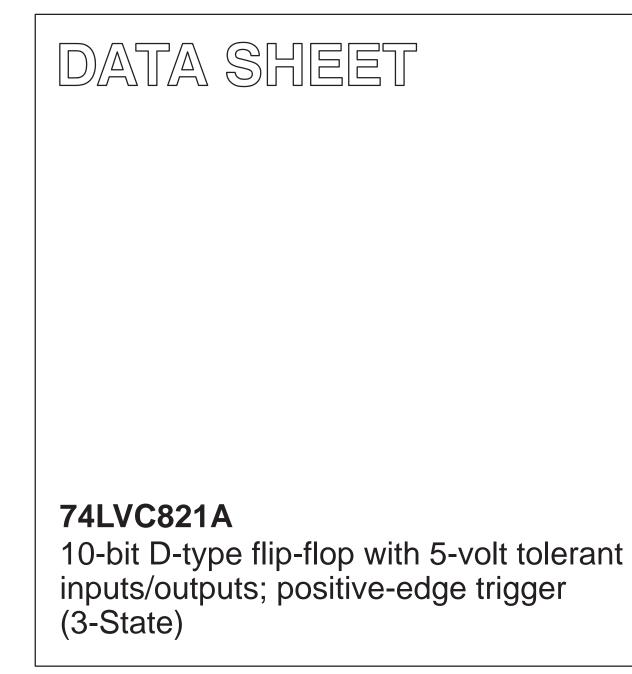
INTEGRATED CIRCUITS



Product specification

1998 Sep 25



74LVC821A

FEATURES

- 5-volt tolerant inputs/outputs, for interfacing with 5-volt logic
- Supply voltage range of 2.7V to 3.6V
- Complies with JEDEC standard no. 8-1A
- Inputs accept voltages up to 5.5V
- CMOS low power consumption
- Direct interface with TTL levels
- 10-bit positive edge-triggered register
- Independent register and 3-State buffer operation
- Flow-through pin-out architecture

DESCRIPTION

The 74LVC821A is a high performance, low-power, low-voltage Si-gate CMOS device and superior to most advanced CMOS compatible TTL families.

Inputs can be driven from either 3.3V or 5.0V devices. In 3-state operation, outputs can handle 5V. This feature allows the use of these devices as translators in a mixed 3.3V/5V environment.

The 74LVC821A is a10-bit D-type flip-flop featuring separate D-type inputs for each flip-flop and 3-State outputs for bus-oriented applications. A clock (CP) and an output enable (\overline{OE}) input are common to all flip-flops. The ten flip-flops will store the state of their individual D-inputs that meet the set-up and hold times requirements on the LOW-to-HIGH CP transition. When \overline{OE} is LOW, the contents of the ten flip-flops is available at the outputs.

When \overline{OE} is HIGH, the outputs go to the high impedance OFF-state. Operation of the \overline{OE} input does not affect the state of the flip-flops.

QUICK REFERENCE DATA

GND = 0 V; $T_{amb} = 25^{\circ}C$; $t_r = t_f \le 2.5$ ns

| SYMBOL | PARAMETER | CONDITIONS | TYPICAL | UNIT |
|--|---|--|---------|------|
| t _{PHL} /t _{PLH} Propagation delay CP to Q _n | | C _L = 50 pF; V _{CC} = 3.3 V | 5.4 | ns |
| f _{max} | Maximum clock frequency | $v_{CC} = 3.3 v$ | 150 | MHz |
| Cl | Input capacitance | | 5.0 | pF |
| C _{PD} | Power dissipation capacitance per flip-flop | Notes 1 and 2 | 26 | pF |

NOTES:

1. C_{PD} is used to determine the dynamic power dissipation (P_D in μ W) $P_D = C_{PD} \times V_{CC}^2 \times f_i + \sum (C_L \times V_{CC}^2 \times f_o)$ where: f_i = input frequency in MHz; C_L = output load capacity in pF; f_o = output frequency in MHz; V_{CC} = supply voltage in V;

 $\sum (C_L \times V_{CC}^2 \times f_0) =$ sum of the outputs.

2. The condition is $V_I = GND$ to V_{CC}

ORDERING INFORMATION

| PACKAGES | TEMPERATURE RANGE | ORDERING CODE | PKG. DWG. # |
|-----------------------------|-------------------|---------------|-------------|
| 24-Pin Plastic SO | -40°C to +85°C | 74LVC821A D | SOT137-1 |
| 24-Pin Plastic SSOP Type II | -40°C to +85°C | 74LVC821A DB | SOT340-1 |
| 24-Pin Plastic TSSOP Type I | -40°C to +85°C | 74LVC821A PW | SOT355-1 |

74LVC821A

PIN DESCRIPTION

| PIN NUMBER | SYMBOL | NAME AND FUNCTION |
|--|-----------------|--|
| 1 | ŌĒ | Output enable input (active LOW) |
| 2, 3, 4, 5, 6, 7, 8, 9, 10, 11 | D_0 to D_9 | Data inputs |
| 23, 22, 21, 20, 19, 18, 17, 16, 15, 14 | Q_0 to Q_9 | 3-State flip-flop outputs |
| 12 | GND | Ground (0 V) |
| 13 | СР | Clock input (LOW-to-HIGH, edge-triggered) |
| 24 | V _{CC} | Positive supply voltage |

FUNCTION TABLE

| OPERATING MODES | | INPUTS | | INTERNAL FLIP-FLOPS | OUTPUTS |
|-----------------------------------|--------|---------------------|----------------|---------------------|----------------------------------|
| OPERATING MODES | ŌĒ | СР | D _n | INTERNAL FLIF-FLOFS | Q ₀ to Q ₉ |
| Load and read register | L | $\uparrow \uparrow$ | l h | L H | L H |
| Load register and disable outputs | H H | $\uparrow \uparrow$ | l h | L H | Z Z |
| Hold | L | H or L | Х | NC | NC |

H = HIGH voltage level

h = HIGH voltage level one set-up time prior to the LOW-to-HIGH CP transition

L = LOW voltage level

I = LOW voltage level one set-up time prior to the LOW-to-HIGH

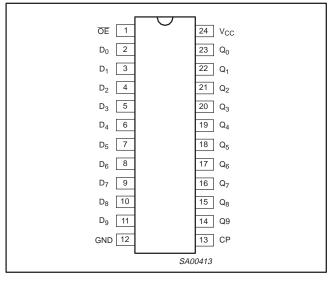
CP transition

Z = high impedance OFF-state

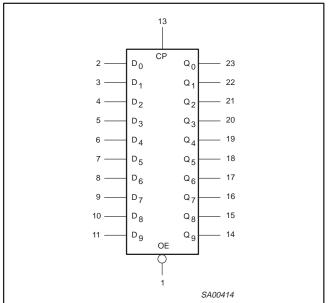
 $\uparrow = LOW-to-HIGH clock transition$

NC= no change

PIN CONFIGURATION

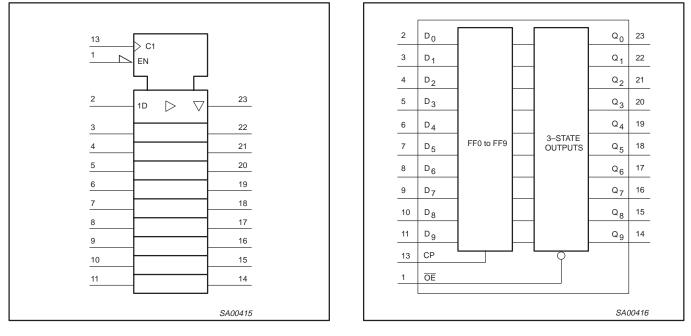


LOGIC SYMBOL



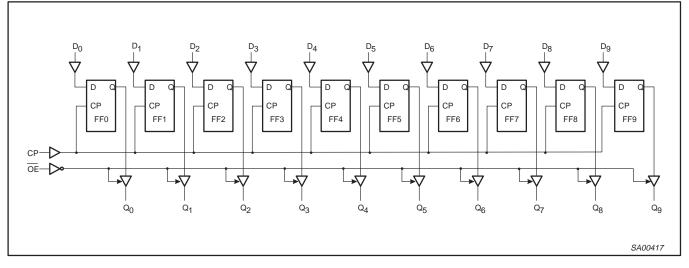
74LVC821A

LOGIC SYMBOL (IEEE/IEC)



FUNCTIONAL DIAGRAM

LOGIC DIAGRAM



74LVC821A

RECOMMENDED OPERATING CONDITIONS

| SYMBOL | DADAMETED | CONDITIONS | LIM | | | |
|---------------------------------|---|--|---------|-----------------|------|--|
| STWBUL | PARAMETER | CONDITIONS | MIN MAX | | UNIT | |
| M | DC supply voltage (for max. speed performance) | | 2.7 | 3.6 | v | |
| V _{CC} | DC supply voltage (for low-voltage applications) | | 1.2 | 3.6 | v | |
| VI | DC Input voltage range | | 0 | 5.5 | V | |
| Vo | DC output voltage range; output HIGH or LOW state | | 0 | V _{CC} | V | |
| - | DC output voltage range; output 3-State | | 0 | 5.5 |] | |
| T _{amb} | Operating ambient temperature range in free-air | | -40 | +85 | °C | |
| t _r , t _f | Input rise and fall times | $V_{CC} = 1.2 \text{ to } 2.7 \text{V}$ $V_{CC} = 2.7 \text{ to } 3.6 \text{V}$ | 0 0 | 20 10 | ns/V | |

ABSOLUTE MAXIMUM RATINGS¹

In accordance with the Absolute Maximum Rating System (IEC 134) Voltages are referenced to GND (ground = 0V)

| SYMBOL | PARAMETER | CONDITIONS | RATING | UNIT |
|------------------------------------|--|--|------------------------------|------|
| V _{CC} | DC supply voltage | | -0.5 to +6.5 | V |
| I _{IK} | DC input diode current | V _I <0 | -50 | mA |
| VI | DC input voltage | Note 2 | -0.5 to +6.5 | V |
| I _{OK} | DC output diode current | $V_{O} > V_{CC} \text{ or } V_{O} < 0$ | ±50 | mA |
| λ/ | DC output voltage; output HIGH or LOW state | Note 2 | -0.5 to V _{CC} +0.5 | V |
| Vo | DC output voltage; output 3-State | Note 2 | -0.5 to 6.5 | v |
| Ι _Ο | DC output source or sink current | $V_{O} = 0$ to V_{CC} | ±50 | mA |
| I _{GND} , I _{CC} | DC V _{CC} or GND current | | ±100 | mA |
| T _{stg} | Storage temperature range | | -65 to +150 | °C |
| P _{TOT} | Power dissipation per package – plastic mini-pack (SO) – plastic shrink mini-pack (SSOP and TSSOP) | above +70°C derate linearly with 8 mW/K above +60°C derate linearly with 5.5 mW/K | 500 500 | mW |

NOTES:

 Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

2. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

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DC ELECTRICAL CHARACTERISTICS

Over recommended operating conditions voltages are referenced to GND (ground = 0V)

| | | L 1 | | UNIT | | |
|------------------|---|---|-----------------------|------------------|------|-----|
| SYMBOL | PARAMETER | TEST CONDITIONS | Temp = -40°C to +85°C | | | |
| | | | MIN | TYP ¹ | МАХ | 1 |
| M | | V _{CC} = 1.2V | V _{CC} | | | v |
| VIH | HIGH level Input voltage | V _{CC} = 2.7 to 3.6V | 2.0 | | | 1 × |
| M | | V _{CC} = 1.2V | | | GND | v |
| VIL | LOW level Input voltage | V _{CC} = 2.7 to 3.6V | | | 0.8 | 1 × |
| | | $V_{CC} = 2.7V; V_I = V_{IH} \text{ or } V_{IL}; I_O = -12mA$ | V _{CC} -0.5 | | | |
| M | V _{OH} HIGH level output voltage | $V_{CC} = 3.0V; V_I = V_{IH} \text{ or } V_{IL}; I_O = -100 \mu A$ | V _{CC} -0.2 | V _{CC} | | |
| ∨он | | $V_{CC} = 3.0V; V_I = V_{IH} \text{ or } V_{IL}; I_O = -18\text{mA}$ | V _{CC} -0.6 | | | Ň |
| | | $V_{CC} = 3.0V; V_I = V_{IH} \text{ or } V_{IL}; I_O = -24mA$ | V _{CC} -0.8 | | |] |
| | | $V_{CC} = 2.7V; V_I = V_{IH} \text{ or } V_{IL}; I_O = 12mA$ | | | 0.40 | |
| V _{OL} | LOW level output voltage | $V_{CC} = 3.0V; V_I = V_{IH} \text{ or } V_{IL}; I_O = 100 \mu A$ | | | 0.20 | V |
| | | $V_{CC} = 3.0V; V_I = V_{IH} \text{ or } V_{IL}; I_O = 24mA$ | | | 0.55 | |
| ł | Input leakage current | $V_{CC} = 3.6V; V_{I} = 5.5V \text{ or GND}$ | | ±0.1 | ±5 | μΑ |
| I _{OZ} | 3-State output OFF-state current | $V_{CC} = 3.6V; V_I = V_{IH} \text{ or } V_{IL}; V_O = 5.5V \text{ or GND}$ | | 0.1 | ±5 | μA |
| I _{off} | Power off leakage supply | $V_{CC} = 0.0V; V_1 \text{ or } V_0 = 5.5V$ | | 0.1 | ±10 | μA |
| I _{CC} | Quiescent supply current | $V_{CC} = 3.6V; V_I = V_{CC} \text{ or } \text{GND}; I_O = 0$ | | 0.1 | 10 | μΑ |
| ΔI_{CC} | Additional quiescent supply current per input pin | V_{CC} = 2.7V to 3.6V; V_{I} = V_{CC} –0.6V; I_{O} = 0 | | 5 | 500 | μΑ |

NOTES:

1. All typical values are at $V_{CC} = 3.3V$ and $T_{amb} = 25^{\circ}C$. 2. The specified overdrive current at the data input forces the data input to the opposite logic input state.

AC CHARACTERISTICS

GND = 0V; $t_r = t_f \le 2.5 \text{ns}$; $C_L = 50 \text{pF}$; $R_L = 500 \Omega$; $T_{amb} = -40^{\circ} \text{C}$ to +85°C.

| | | | LIMITS | | | | | | |
|--------------------------------------|--|--------------|--------|------------------------|-----|-------------------|--------|------|--|
| SYMBOL | PARAMETER | WAVEFORM | Vcc | _C = 3.3V ±0 | .3V | V _{CC} = | : 2.7V | UNIT | |
| | | | MIN | TYP ¹ | MAX | MIN | MAX | | |
| t _{PHL} t _{PLH} | Propagation delay CP to Q _n | Figures 1, 4 | 1.5 | 5.4 | 7.3 | 1.5 | 8.5 | ns | |
| t _{PZH} t _{PZL} | $\frac{3}{OE}$ to Q_n | Figures 2, 4 | 1.5 | 5.5 | 7.6 | 1.5 | 8.8 | ns | |
| t _{PHZ} t _{PLZ} | $\frac{3-\text{State output disable time}}{\text{OE}}$ to Q_{n} | Figures 2, 4 | 1.5 | 3.8 | 6.2 | 1.5 | 6.8 | ns | |
| t _W | Clock pulse width HIGH or LOW | Figure 1 | 3.3 | 1.7 | - | 3.3 | - | ns | |
| t _{SU} | Setup time D _n to CP | Figure 3 | 1.9 | 0.6 | - | 0.9 | - | ns | |
| t _h | Hold time D _n to CP | Figure 3 | 1.5 | 0 | - | 1.5 | - | ns | |
| f _{max} | Maximum clock pulse frequency | Figure 1 | 150 | 200 | - | 150 | - | MHz | |

NOTE:

1. Unless otherwise stated, all typical values are at V_{CC} = 3.3V and T_{amb} = 25^{\circ}C.

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AC WAVEFORMS

 V_M = 1.5V at $V_{CC} \ge$ 2.7V; V_M = 0.5 V_{CC} at $V_{CC} <$ 2.7V. V_{OL} and V_{OH} are the typical output voltage drop that occur with the output load.

 V_X = V_{OL} + 0.3V at V_{CC} \geq 2.7V; V_X = V_{OL} + 0.1 V_{CC} at V_{CC} < 2.7V V_Y = V_{OH} –0.3V at V_{CC} \geq 2.7V; V_Y = V_{OH} –0.1 V_{CC} at V_{CC} < 2.7V

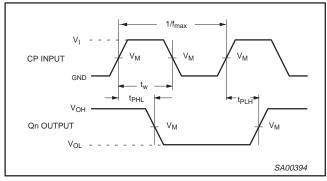


Figure 1. Clock (CP) to output (Q_n) propagation delays, the clock pulse width and the maximum clock pulse frequency.

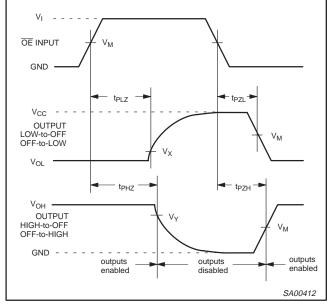


Figure 2. 3-State enable and disable times.

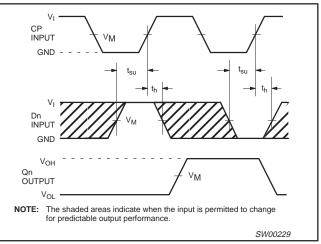


Figure 3. Data setup and hold times for the D_{n} input to the CP input.

TEST CIRCUIT

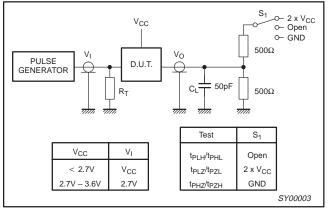
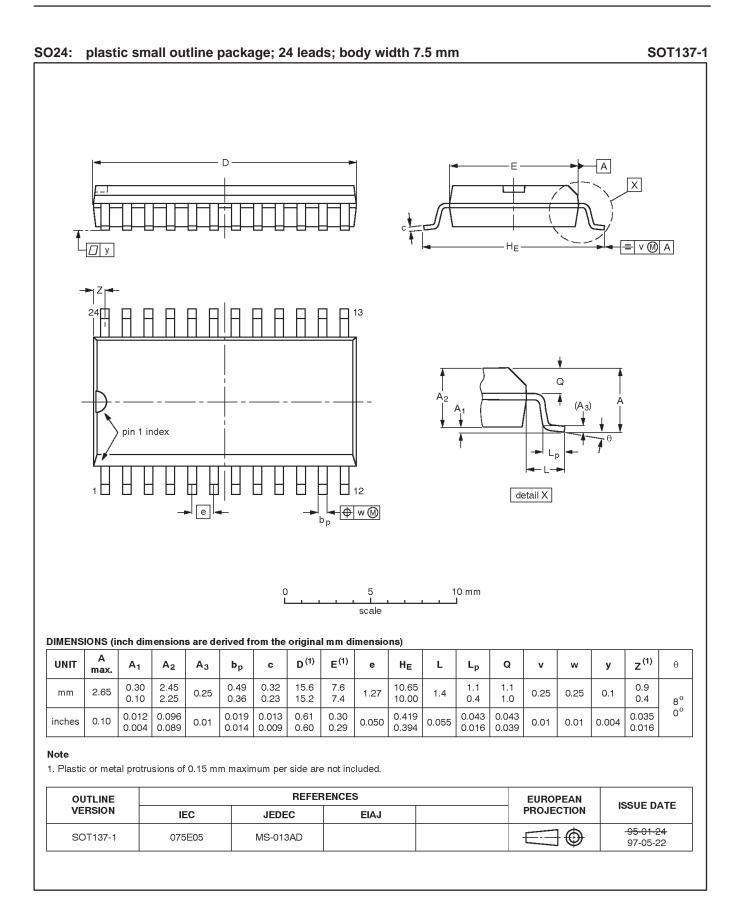
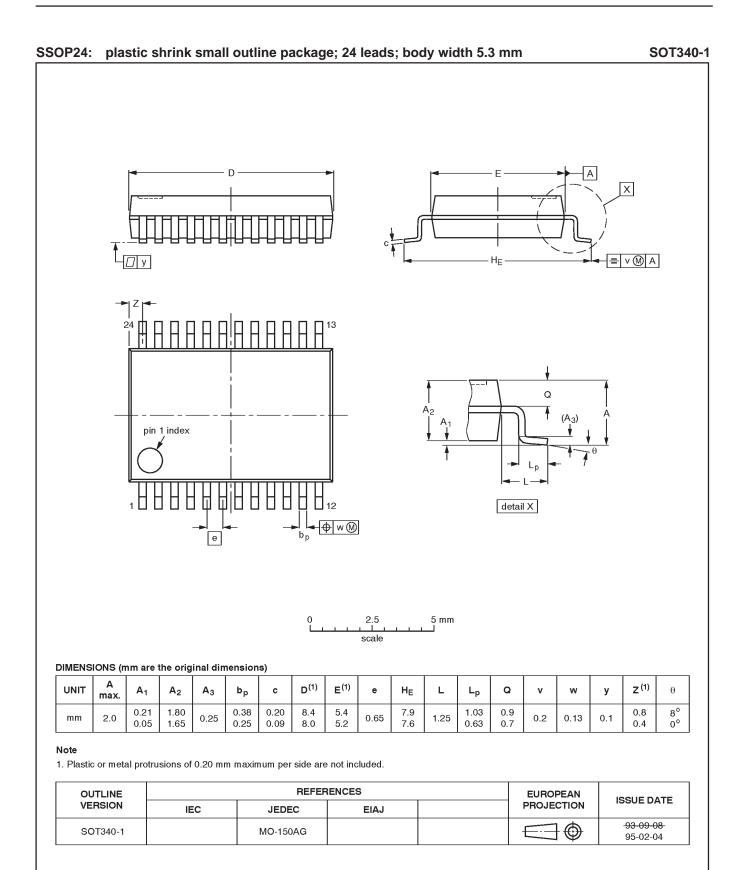


Figure 4. Load circuitry for switching times.

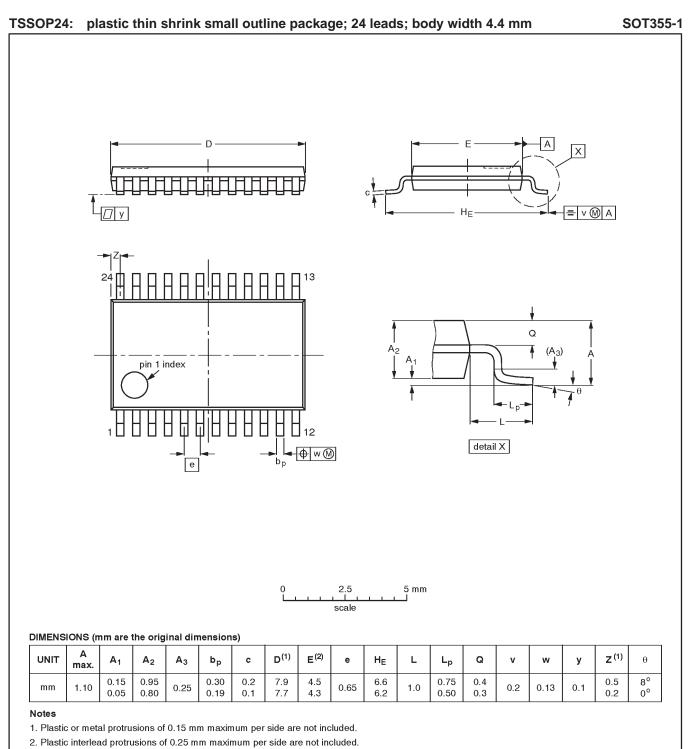
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| OUTLINE | REFERENCES | | | EUROPEAN | ISSUE DATE | |
|----------|------------|----------|------|----------|------------|-----------------------------------|
| VERSION | IEC | JEDEC | EIAJ | | PROJECTION | ISSUE DATE |
| SOT355-1 | | MO-153AD | | | | -93-06-16- 95-02-04 |

74LVC821A

NOTES

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Data sheet status

| Data sheet status | Product status | Definition [1] |
|---------------------------|-------------------|---|
| Objective specification | Development | This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice. |
| Preliminary specification | Qualification | This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product. |
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[1] Please consult the most recently issued datasheet before initiating or completing a design.

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Limiting values definition - Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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